

INFORMATION DISCLOSURE STATEMENT BY APPLICANT PTO FORM 1449	Atty. Docket No. 10191/2287		Serial No. To Be Assigned
	Applicant(s) Michael LINDNER et al.		
	Filing Date Herewith	Group To Be Assigned	

U. S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NUMBER	PATENT DATE	NAME	CLASS	SUBCLASS	FILING DATE
SAT	5,933,237*	August 3, 1999	Drabarek			
SAT	5,493,398*	February 20, 1996	Pfister			
SAT	5,155,363*	October 13, 1992	Steinbichler et al.			
SAT	3,849,003*	November 19, 1974	Velzel			

*Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority, and relevance noted in Search Report, copy of which is enclosed herewith).

FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
						YES	NO
SAT	197 21 842***	December 3, 1998	DE				
↑	41 08 944***	September 24, 1992	DE				
	WO 92 19930*	November 12, 1992	PCT				
	03 120436*	May 22, 1991	JP				
↓	196 25 830*	January 2, 1998	DE				
SAT	197 21 843**	February 11, 1999	DE				

*Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority, and relevance noted in Search Report, copy of which is enclosed herewith).

** Described in Specification.

OTHER DOCUMENTS

EXAMINER'S INITIALS	AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
SAT	Patent Abstracts of Japan, vol. 015, no. 327 (P-1240), (August 20, 1991).*
SAT	P. de Groot, L. Deck, "Surface Profiling by Analysis of White-Light Interferograms in the Spatial Frequency Domain" J. Mod. Opt., Vol. 42, No. 2, 389-401, (1995)."
SAT	No. T. Maack, G. Notni, W. Schreiber, W.-D. Prenzel, "Endoscopic 3-D Shape Measuring System", Jahrbuch fur Optik und Feinmechanik, Ed. W.-D. Prenzel, 231-240, (1998)."

*Copy of reference is not enclosed because reference is cited in Search Report (copy of reference provided by International Searching Authority, and relevance noted in Search Report, copy of which is enclosed herewith).

** Described in Specification.

EXAMINER <i>S.A. Turner</i>	DATE CONSIDERED 6-25-04
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	